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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT: Erich Gornick et al

TITLE: METHOD AND DRVICE FOR OPTICALLY TESTING
SEMICONDUCTOR ELEMENTS

THE COMMISSIONER FOR PATENTS
P.O. Box 1450
Alexandria, VA 22313-1450

PRELIMINARY AMENDMENT

Sir:

This is a preliminary amendment accompanying a new patent application being filed simultaneously herewith.

IN THE CLAIMS:

Please replace the claims with the attached amended claims.

REMARKS

The claims have been amended to remove the improper multiple dependencies, reference numerals and characterizing language, and to correct informalities. No new matter has been added.

Respectfully submitted,



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Date